

**Notic of References Cited**

Application/Control No.

09/420,719

Applicant(s)/Patent Under  
Reexamination  
MIYASHITA ET AL.

Examiner

Kartic Padmanabhan

Art Unit

1641

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,582,697	12-1996	Ikeda et al.	204/403.11
*	B	US-6,007,775	12-1999	Yager, Paul	422/57
*	C	US-5,628,897	05-1997	Phelan, John J.	210/149
	D	US-5,571,419	11-1996	Obata et al.	210/664
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.